## Supporting Information

## Hybrid chalcogenide nanoparticles: 2D-WS<sub>2</sub> nanocrystals inside nested WS<sub>2</sub> fullerenes

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**Figure S1.** TEM images of the primary product obtained after the first step at 600°C. (a) Clusters of spherical particles, (b) Intergrown spherical particles (shown by an arrow).

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**Figure S2.** Rietveld-refinement of the x-ray diffraction pattern of the final product (red dots: observed intensity, black line: model, red line: difference cureve, ticks marks the reflection positions of 2H-WS<sub>2</sub> (black, W.J. Schutte, J.L. DeBoer, F. Jellinek, *J. Solid State Chem.* 1987, **70**, 207-209) and 3R-WS<sub>2</sub>, (F. Jellinek, J.C. Wildervanck, Z. Anorg. Allg. Chem. 1964, **328**, 309-318 ).

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Table S1. Measurement and refinemt parameter of the Rietveld refinement of the final product

Diffractometer	Siemens D5000
Sample preparation	Fine powder fixed between two stripes of Scotch <sup>TM</sup> tape
Measuring mode	Transmission
Wavelength	1.540596
Measuring range	$10 \le 2\Theta /^{\circ} \le 90; \ 0.71 \le Q / \text{Å}^{-1} \le 5.77$
Temperature /K	298K
Profile Fit	Rietveld refinement according to reported crystal structure models
Background / Parameters	Chebyshev / 15
Profile function	Fundamental Parameters Approach
Program	TOPAS Academic V5.1
Total No. of Parameters	23
R <sub>exp</sub>	4.6
R <sub>wp</sub>	13.0
GoF	2.86
Phase I	WS <sub>2</sub> -2H
Space group	P6 <sub>3</sub> /mmc
Cell parameters /Å	a = 3.151(1) Å, $c = 12.600(5)$ Å
Crystallite size / nm	10(1)
Fraction /%wt	34(2)
Biso	2.8(1)
Phase II	WS <sub>2</sub> -3R
Space group	R3m (hexagonal setting)
Cell parameters /Å	a = 3.151(1) Å, $c = 18.900(5)$ Å
Crystallite size / nm	6(1)
Fraction /%wt	66(2)
Biso	2.8(1)



Figure S3. TEM overview image of the product obtained at the annealing temperature of 750°C



Figure S4. TEM overview image of the product obtained at the annealing temperature of 800°C.



Figure S5. TEM overview image of the product obtained at the annealing temperature of 900°C.

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Figure S6. TEM images of the products obtained from reactions at (a) 300°C, (b) 400°C and (c) 500°C.



Figure S7. TEM image of the annealed product obtained (a) without iodine and (b) for a  $W(CO)_6/I_2$  ratio of 1:1.



Figure S8. (a) AFM height profile of as-synthesized IF-WS<sub>2</sub> particle. (b) Phase profile of IF-WS<sub>2</sub> particles.